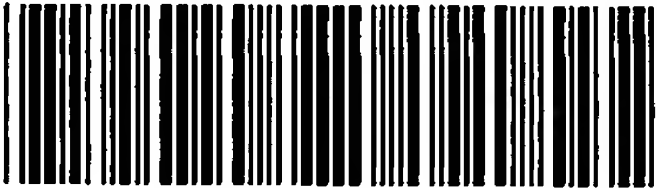


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/573,264	PELED ET AL.	
	Examiner	Art Unit	
	Son T. Nguyen	3643	

SEARCHED			
Class	Subclass	Date	Examiner
47	20.1 29.4	7/20/2007	STN
	31 31.1		
	32 32.3		
	58.1R		
	58.1SC		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
IPC foreign search, see printouts	7/20/2007	STN
text search, see printouts	7/20/2007	STN